## . .. . Applicant(s)/Patent Under Application/Control No. Reexamination 10/032,884 CHEN, SHIH-WEN Notice of References Cited Examiner Art Unit Page 1 of 1 Peter B. Kim 2851 **U.S. PATENT DOCUMENTS** Date **Document Number** Classification Name Country Code-Number-Kind Code MM-YYYY 358/453 US-2002/0176120 11-2002 O'Callaghan et al. Α 355/27 US-6,222,607 04-2001 Szajewski et al. В С US-D US-US-Ε F US-G US-Н USţ US-US-J Κ US-US-L US-М FOREIGN PATENT DOCUMENTS **Document Number** Date Country Name Classification Country Code-Number-Kind Code MM-YYYY Ν 0 Р Q R S

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